



AE/2829  
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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	Bruce et al.	Examiner:	Chan, E.
Serial No.:	09/915,883	Group Art Unit:	2829
Filed:	July 26, 2001	Docket No.:	AMDA.508PA
Title:	Integrated Circuit Defect Analysis Using Liquid Crystal		

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence and the papers, as described hereinabove, are being deposited in the United States Postal Service, as first class mail, in an envelope addressed to: Mail Stop AF, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on July 13, 2004.

By: Erin M. Nichols  
Erin M. Nichols

**OFFICE ACTION RESPONSE AFTER FINAL**

Mail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Madam:

In response to the final Office Action dated May 20, 2004, please consider the following amendment and remarks.

Amendments to the claims are reflected in the listing of claims beginning at page 2 and the Remarks begin on page 7.

Enclosed please find a Terminal Disclaimer under 37 C.F.R. §1.321(c).